

Appl. No. 10/707,933
Amdt. dated May 10, 2006
Reply to Office action of March 06, 2006

REMARKS/ARGUMENTS

1. Amendment to claim 11:

Claim 11 is amended to solve the problem of the unclear description of the passivation layer. The passivation layer in the applicant's invention is made of material having varying organic/inorganic ratios, and each organic/inorganic ratio of the material has a different thickness. This is supported in the specification, "By reducing the ratio between the reactant sources of the organic compounds and the inorganic compounds continuously during the fabricating process, the organic/inorganic ratio of the formed organic/inorganic composite film is also decreasing gradually" and "a part of the organic/inorganic film first formed has a organic/inorganic ratio higher than that of a part of the organic/inorganic film formed subsequently and being farther from the organic light emitting display unit 114". As shown above, the amended claim 11 is totally supported by the specification. Thus, no new matter is added.

2. Rejection of claims 11-26 under 35 U.S.C. 102 (b) as being anticipated by Shi et al. (US 5,811,177) .

In Shi et al., the active organic media 13 and the array of organic LEDs 11 are covered by the buffer layer 22 and the low permeability inorganic layer 26. The buffer layer 22 is made of the lower coefficients of thermal expansion (CTE) organic material. The low permeability inorganic layer 26 is made of the higher (CTE) inorganic material. The thermal coefficient matching layer 24 is a buffer layer between them. Please notice, the CTE is concerned with coefficients of thermal expansion, not concentration.

In the applicant's invention, the every part of the passivation layer is made of different organic/inorganic ratios. This is illustrated in the specification of the applicant's invention "an organic/inorganic film formed of a SiO_xCyHz compound covering the organic light emitting display unit 114 and the substrate 112. In the same manner, different methods can be used to control the ratio among x, y, and z in the fabricating

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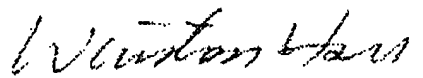
process so that the SiO_xCyHz compound formed earlier has a higher organic/inorganic ratio, which has a higher y and z, and the organic/inorganic ratio decreases gradually, in which y and z are smaller, in the latter fabrication."

5 The amended claim 11 is different from Shi et al. (US 5,811,177). Each of the buffer layer 22, the thermal coefficient matching layer 24, and the low permeability inorganic layer 26 is a single layer in Shi et al. (US 5,811,177). But, the passivation layer of the applicant's invention has variable organic/inorganic ratios. The different organic/inorganic ratios are mixed in the passivation layer. So, the passivation layer is a single layer having
10 variable organic/inorganic ratios. Thus, the structures of Shi et al. and the applicant's are different.

Thus, the amended claim 11 is patentably distinguishable from Shi et al. (US 5,811,177). Reconsideration of the amended claims is politely requested.

15 Applicant respectfully requests that a timely Notice of Allowance be issued in this case.

Sincerely yours,



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